

Hits	Search Text	DBs	Time Stamp
1 17	source and drain and gate and ((ramp or ramped) with threshold) and control and longitudinal	US-PGPUB; USPAI; 2005/02/11 EPO; JPO; DERMENT; 15:12	2005/02/11 15:12
2 2	source and drain and gate and ((ramp or ramped) with threshold) and control and longitudinal and @pd>"20040909"	US-PGPUB; USPAI; 2005/02/11 EPO; JPO; DERMENT; 15:12	2005/02/11 15:12
3 4	S33 S34 S35 S36 S37	US-PGPUB; USPAI; 2005/02/11 EPO; JPO; DERMENT; 15:12	2005/02/11 15:12
4 27	((mos and source and drain and gate and (control adj gate)) and ((257/368,E21.681,E21.685.ccls. 365/185.26.ccls.)) not ((mos and source and drain and gate and (control adj gate)) and 257/368,E21.681,E21.685.ccls.)) and split	US-PGPUB; USPAI; 2005/02/11 EPO; JPO; DERMENT; 15:11	2005/02/11 15:11
5 13	(mos and source same drain same gate same (control adj gate) same threshold) and 257/368,E21.681,E21.685.ccls.	US-PGPUB; USPAI; 2005/02/11 EPO; JPO; DERMENT; 15:11	2005/02/11 15:11
6 10	((gate adj oxide adj thickness) with threshold) and source and drain and gate and (ramp or ramped)	US-PGPUB; USPAI; 2005/02/11 EPO; JPO; DERMENT; 15:11	2005/02/11 15:11
7 4	((gate) with threshold) and source and drain and gate and ((ramp or ramped) with threshold) and control and longitudinal	US-PGPUB; USPAI; 2005/02/11 EPO; JPO; DERMENT; 15:11	2005/02/11 15:11
8 1	((mos and source and drain and gate and (control adj gate)) and ((257/368,E21.681,E21.685.ccls. 365/185.26.ccls.)) not ((mos and source and drain and gate and (control adj gate)) and 257/368,E21.681,E21.685.ccls.)) and split and @pd>"20040909"	US-PGPUB; USPAI; 2005/02/11 EPO; JPO; DERMENT; 15:11	2005/02/11 15:11
9 1	(mos and source same drain same gate same (control adj gate) same threshold) and 257/368,E21.681,E21.685.ccls. and @pd>"20040909"	US-PGPUB; USPAI; 2005/02/11 EPO; JPO; DERMENT; 15:11	2005/02/11 15:11
10 0	((gate adj oxide adj thickness) with threshold) and source and drain and gate and (ramp or ramped) and @pd>"20040909"	US-PGPUB; USPAI; 2005/02/11 EPO; JPO; DERMENT; 15:11	2005/02/11 15:11
11 0	((gate) with threshold) and source and drain and gate and ((ramp or ramped) with threshold) and control and longitudinal and @pd>"20040909"	US-PGPUB; USPAI; 2005/02/11 EPO; JPO; DERMENT; 15:11	2005/02/11 15:11
12 1	((variable) with threshold) and source and drain and gate and ((ramp or ramped) with threshold) and control and transistor and "257"/s.ccls.	US-PGPUB; USPAI; 2004/09/10 EPO; JPO; DERMENT; 11:24	2004/09/10 11:24
13 38	((variable) with threshold) and source and drain and gate and ((ramp or ramped) with threshold) and control and transistor	US-PGPUB; USPAI; 2004/09/10 EPO; JPO; DERMENT; 11:23	2004/09/10 11:23
14 259	((gate) with threshold) and source and drain and gate and ((ramp or ramped) with threshold) and control and transistor	US-PGPUB; USPAI; 2004/09/10 EPO; JPO; DERMENT; 11:22	2004/09/10 11:22
15 0	((gate) with threshold) and source and drain and gate and ((ramp or ramped) with threshold) and control and transistor and 257/368,E21.681,E21.685.ccls.	US-PGPUB; USPAI; 2004/09/10 EPO; JPO; DERMENT; 11:11	2004/09/10 11:11
16 33	((gate) with threshold) and source and drain and gate and ((ramp or ramped) with threshold) and control and transistor and "257"/s.ccls.	US-PGPUB; USPAI; 2004/09/10 EPO; JPO; DERMENT; 11:11	2004/09/10 11:11
17 1295	257/368,E21.681,E21.685.ccls.	US-PGPUB; USPAI; 2004/09/10 EPO; JPO; DERMENT; 11:10	2004/09/10 11:10
18 285	((gate) with threshold) and source and drain and gate and ((ramp or ramped) with threshold) and control	US-PGPUB; USPAI; 2004/09/10 EPO; JPO; DERMENT; 11:10	2004/09/10 11:10
19 1285	257/368,E21.681,E21.685.ccls.	US-PGPUB; USPAI; 2004/09/10 EPO; JPO; DERMENT; 11:10	2004/09/10 11:10
20 0	source and drain and gate and ((ramp or ramped) same threshold same longitudinal) and control	US-PGPUB; USPAI; 2004/09/10 EPO; JPO; DERMENT; 11:09	2004/09/10 11:09
21 301	((gate) with threshold) and source and drain and gate and ((ramp or ramped) with threshold)	US-PGPUB; USPAI; 2004/09/10 EPO; JPO; DERMENT; 11:06	2004/09/10 11:06
22 2	"20030030091".pn.	US-PGPUB; USPAI; 2004/09/09 EPO; JPO; DERMENT; 16:44	2004/09/09 16:44
23 306	((gate adj oxide adj thickness) with threshold) and source and drain and gate	US-PGPUB; USPAI; 2004/09/09 EPO; JPO; DERMENT; 16:44	2004/09/09 16:44
24 1687	mos and source same drain same gate same (control adj gate) same threshold	US-PGPUB; USPAI; 2004/09/09 EPO; JPO; DERMENT; 16:34	2004/09/09 16:34
25 1295	257/368,E21.681,E21.685.ccls.	US-PGPUB; USPAI; 2004/09/09 EPO; JPO; DERMENT; 16:33	2004/09/09 16:33
26 309	mos and source same drain same gate same (control adj gate) and (split with control)	US-PGPUB; USPAI; 2004/09/09 EPO; JPO; DERMENT; 16:31	2004/09/09 16:31
27 86	mos and source same drain same gate same (control adj gate) and (split with control) same side	US-PGPUB; USPAI; 2004/09/09 EPO; JPO; DERMENT; 16:30	2004/09/09 16:30
28 0	mos and source same drain same gate same (control adj gate) and (split with control) same surround	US-PGPUB; USPAI; 2004/09/09 EPO; JPO; DERMENT; 16:29	2004/09/09 16:29
29 377	mos and source and drain and gate and (control adj gate) and (split with control)	US-PGPUB; USPAI; 2004/09/09 EPO; JPO; DERMENT; 16:29	2004/09/09 16:29
30 11	((US-6144075-\$ or US-6040605-\$ or US-5635416-\$ or US-6438028-\$ or US-5587945-\$ or US-5386132-\$ or US-5218568-\$ or US-4654825-\$).did. or (US-2002014316-\$ or US-20020125336-\$).did. and (control adj gate)	US-PGPUB; USPAI; 2004/09/09 EPO; JPO; DERMENT; 13:59	2004/09/09 13:59
31 9	((US-6144075-\$ or US-6040605-\$ or US-5635416-\$ or US-6438028-\$ or US-5587945-\$ or US-5386132-\$ or US-5218568-\$ or US-4654825-\$).did. or (US-2002014316-\$ or US-20020125336-\$).did. and (control adj gate)	US-PGPUB; USPAI; 2004/09/09 EPO; JPO; DERMENT; 13:59	2004/09/09 13:59
32 11	((US-6144075-\$ or US-6040605-\$ or US-5635416-\$ or US-6438028-\$ or US-5587945-\$ or US-5386132-\$ or US-5218568-\$ or US-4654825-\$).did. or (US-2002014316-\$ or US-20020125336-\$).did. and (control adj gate)	US-PGPUB; USPAI; 2004/09/09 EPO; JPO; DERMENT; 13:59	2004/09/09 13:59

Updated EAST 2/11/05